

Single and Double Slit Experiments

I. EQUIPMENT LIST

- Optics Bench
- (3) Optics Bench Clamps
- He-Ne Laser
- Single-slit Slide
- Adjustable Slit
- Double-slit Slide
- Screen or whiteboard

II. BACKGROUND INFORMATION

One of the attributes of a wave is its ability to flare out behind barriers or openings/slits. Huygens' principle can be useful in explaining this behavior. Each point on the wave front acts as a secondary point source so some of the wave will propagate in directions NOT perpendicular to the edge. This phenomenon occurs for a "single slit" opening in an opaque material, as well as for "double slit" openings, resulting in the wave "flaring" around the edges of the openings, and producing interference effects.

Double-slit interference/diffraction with slit separation d

The condition for interference maxima for a double slit is given by

$$d \sin \theta = m \lambda \quad (1)$$

The intensity pattern for a double slit is given by the following equation

$$I(\theta) = I_m \cos^2 \beta (\sin \alpha / \alpha)^2 \quad \text{where } \beta = (\pi d / \lambda) \sin \theta \text{ and } \alpha = (\pi a / \lambda) \sin \theta \quad (2)$$

Single-slit diffraction with slit width a

The condition for diffraction minima for a single slit is given by

$$a \sin \theta = m \lambda \quad (3)$$

The single slit intensity pattern is given by the following equation where a is the slit width.

$$I(\theta) = I_m (\sin \alpha / \alpha)^2 \quad \text{where } \alpha = (\pi a / \lambda) \sin \theta \quad (4)$$

General slits

The equation for the intensity function for N slits is given by

$$I(\theta) = I_m ((\sin \alpha) / \alpha)^2 ((\sin N\beta) / \sin \beta)^2 \quad (5)$$

III. EXPERIMENTAL PROCEDURE

1. Double Slit

Using a laser, obtain a double slit interference pattern and project it on a relatively distant screen or wall or whiteboard. You should notice a general variation in intensity across this interference pattern. This is the "diffraction envelope" and is related to the width of a single slit, a , whereas the pattern within each envelope is related to the slit separation, d .

- a) Carefully measure the distance from the slits to the projecting surface and make sure it does not change during your measurements.
- b) Measure the distance between bright spots. Take at least four measurements. Create a data table and enter your measurements.
- c) Measure the distance between dark spots. Take at least four measurements.

- d) Count the number of bright interference fringes in the central diffraction maximum and compare to the calculated value.
 - e) Compute the separation between the slits, d , and the slit width, a .
 - f) Compare with the values printed on the slide before changing the setup.
- Note:* do this before putting away the setup.
- g) Repeat for another double-slit on the slide.

2. Single Slit measurements

A. Fixed width single slit

Using the laser and a single-slit slide, obtain a diffraction pattern and project it on a relatively distant screen or wall or whiteboard. Observe the general behavior of the diffraction pattern from a single slit width.

- a) Carefully measure and record the distance from the slits to the projecting surface.
 - b) Measure the distance between four bright spots and record this in a data table.
 - c) Measure the distance between four dark spots and record this information in your data table.
 - d) Use the average value to compute the predicted slit width from the diffraction pattern
 - e) Compare quantitatively the calculated value of the slit width with the value printed on the slide
- Note:* do this calculation before changing the setup.
- f) Repeat for another slit width on the slide.

B. Adjustable-width single slit

Using the adjustable single slit, produce a single slit pattern on the wall

- a) Measure the FWCM (full width of the central maximum)
- b) Measure the distance between 4 dark spots and between 4 bright spots
- c) Calculate the slit width and compare it with the measured width (if possible)

Note: do this before putting away the equipment.

V. CALCULATIONS

- a) For the single and double-slit data compute the separation between the slits (d) and the slit width (a) and compare to the values printed on the slide. Show your results in a table.
- b) Calculate the angle to the first two diffraction minima (Eq.1)
- b) Use MATLAB or EXCEL to compute and plot the intensity patterns I/I_m as represented by Eq. 2 and 4 for one of each of the setups.

Compare with your experimental patterns.

Vary the parameters a and d and briefly describe your results.

VI. QUESTIONS

Consider a continuous spectrum such as that obtained using white light: is it possible for the first-order maximum for a given wavelength to overlap the second-order maximum for a different wavelength? Justify by showing your calculations.